



FQD1N60C / FQU1N60C

600V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

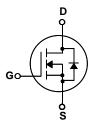
Features

- 1A, 600V, $R_{DS(on)} = 11.5\Omega @V_{GS} = 10 V$
- Low gate charge (typical 4.8nC)
- Low Crss (typical 3.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD1N60C / FQU1N60C	Units
V_{DSS}	Drain-Source Voltage		600	V
I _D	Drain Current - Continuous (T _C = 25°C)		1	Α
	- Continuous (T _C = 100	0.6	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	4	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	33	mJ
I _{AR}	Avalanche Current	(Note 1)	1	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
	Power Dissipation (T _A = 25°C)*		2.5	W
P_D	Power Dissipation (T _C = 25°C)		28	W
	- Derate above 25°C		0.22	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
R _{0JC} Thermal Resistance, Junction-to-Case			4.53	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		50	°C/W
R _{0JA} Thermal Resistance, Junction-to-Ambient			110	°C/W

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	600			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C		0.6		V/°C
I _{DSS}	7 0 1 1/1 5 1 0 1	V _{DS} = 600 V, V _{GS} = 0 V			1	μА
	Zero Gate Voltage Drain Current	V _{DS} = 480 V, T _C = 125°C	-		10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V	-		-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.5 A		9.3	11.5	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 0.5 A (Note 4)	-	0.75		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	 	130 19 3.5	170 25 4.5	pF pF pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time			7	24	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_{D} = 1.1 \text{ A},$ $R_{G} = 25 \Omega$	-	21	52	ns
t _{d(off)}	Turn-Off Delay Time	R _G - 25 \(\Omega\)	-	13	36	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	-	27	64	ns
$\overline{Q_g}$	Total Gate Charge	V _{DS} = 480 V, I _D = 1.1 A,	-	4.8	6.2	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V	-	0.7		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)	-	2.7		nC
	Source Diode Characteristics a					
l _S	Maximum Continuous Drain-Source Diode Forward Current				1	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				4	A
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_S = 0.5 \text{ A}$			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 1.1 \text{ A,}$		190		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.53		μC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 59 mH, I_{AS} = 1.1 A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. $I_{SD} \le$ 1.1 A, di/dt \le 200A/ μ s, $V_{DD} \le$ BV $_{DSS}$, Starting T_J = 25°C 4. Pulse Test : Pulse width \le 300 μ s, Duty cycle \le 2% 5. Essentially independent of operating temperature

Typical Characteristics

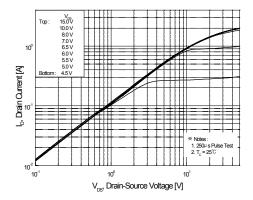


Figure 1. On-Region Characteristics

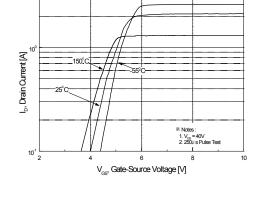


Figure 2. Transfer Characteristics

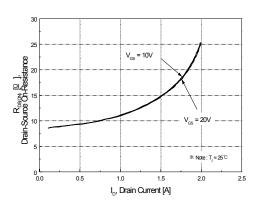


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

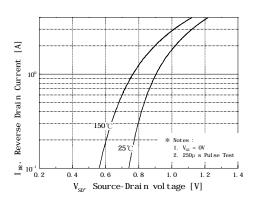


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

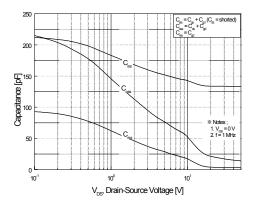


Figure 5. Capacitance Characteristics

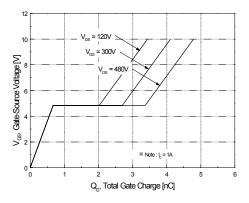
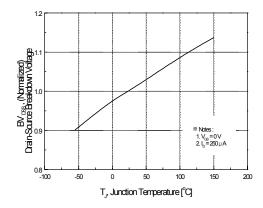


Figure 6. Gate Charge Characteristics

©2009 Fairchild Semiconductor Corporation Rev. A1, January 2009

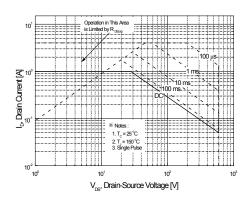
Typical Characteristics (Continued)



(SEC) 1.5 (SEC)

Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



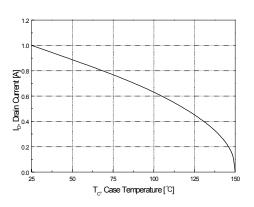


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

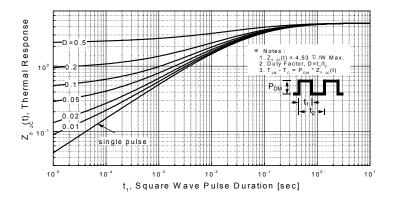
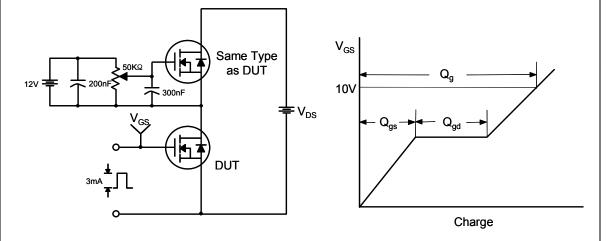


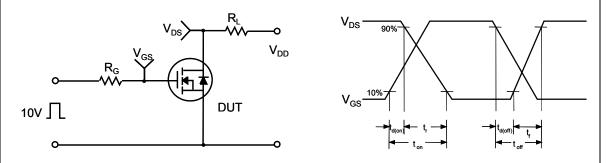
Figure 11. Transient Thermal Response Curve

©2009 Fairchild Semiconductor Corporation Rev. A1, January 2009

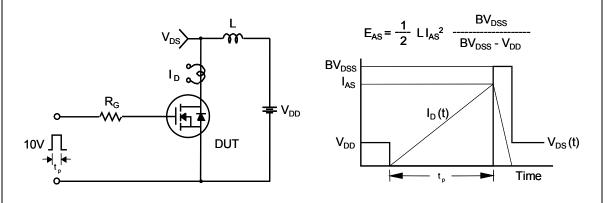
Gate Charge Test Circuit & Waveform



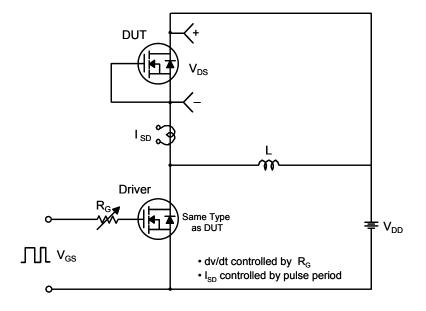
Resistive Switching Test Circuit & Waveforms

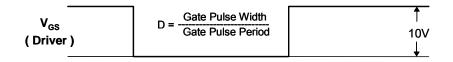


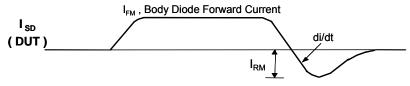
Unclamped Inductive Switching Test Circuit & Waveforms



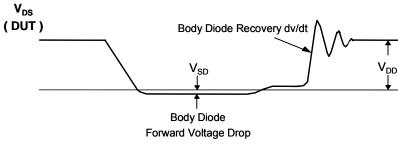
Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Reverse Current

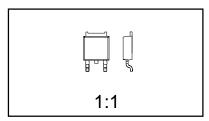


©2009 Fairchild Semiconductor Corporation Rev. A1, January 2009

Mechanical Dimensions

TO-252 (DPAK) (FS PKG Code 36)

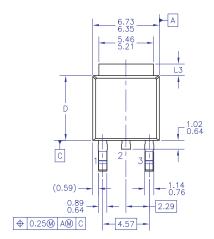


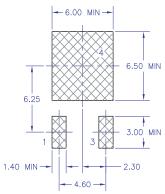


Scale 1:1 on letter size paper

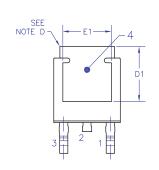
Dimensions shown below are in: millimeters

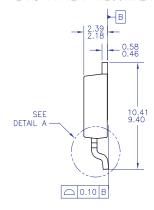
Part Weight per unit (gram): 0.33

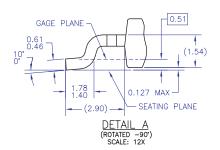




LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

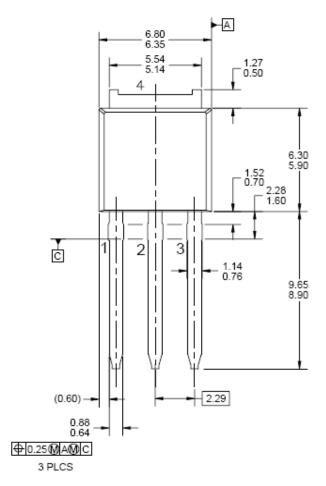
- UNLESS OTHERWISE SPECIFIED
 ALL DIMENSIONS ARE IN MILLIMETERS.
 THIS PACKAGE CONFORMS TO JEDEC, TO-252,
 ISSUE C, VARIATION AA & AB, DATED NOV. 1999.
 DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-1994.
 HEAT SINK TOP EDGE COULD BE IN CHAMFERED
 CORNERS OR EDGE PROTRUSION.
 DIMENSIONS L3,D,E1&D1 TABLE:

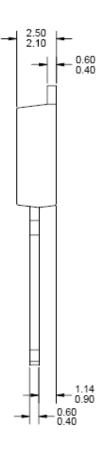
 [OPTION AA JOPTION AB]

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN

Mechanical Dimensions

I - PAK







Dimensions in Millimeters





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Build it Now™ CorePLUS™ CorePOWER™ $CROSSVOLT^{\text{TM}}$ CTL™ Current Transfer Logic™

FcoSPARK® EfficentMax™ EZSWITCH™ *

airchild®

Fairchild Semiconductor® FACT Quiet Series™

FACT® $\mathsf{FAST}^{\circledR}$ FastvCore™ FlashWriter® * FPS™ F-PFS™

FRFET® Global Power ResourceSM Green FPS™ Green FPS™ e-Series™ GTO™

IntelliMAX™ ISOPI ANAR™ MegaBuck^{TI} MICROCOUPLER™ MicroFET™

MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™

Programmable Active Droop™ QFET QSTM Quiet Series™ RapidConfigure™

Saving our world, 1mW /W /kW at a time™ SmartMax™ SMART START™ SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8

SyncFET™ SYSTEM ® GENERAL The Power Franchise®

SupreMOS™

prewer TinyBoost™ TinyBuck™ TinyLogic[®] TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ XS™

* EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

EIPE SUPPORT FOLICE.

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Farichild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Farichild strongly encourages customers to purchase Farichild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Farichild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I37